

Search Notes

Application/Control No.

10/537,329

Examiner

LOIS ZHENG

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

1793

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	10/13/2008	LLZ
Updated EAST search	10/13/2008	LLZ